

RoHS

## **IXFP5N50PM-VB** Datasheet

# N-Channel 650V (D-S) Power MOSFET

PRODUCT SUMMARY				
V <sub>DS</sub> (V) at T <sub>J</sub> max.	650			
R <sub>DS(on)</sub> at 25 °C (Ω)	$V_{GS} = 10 V$	1.1		
Q <sub>g</sub> max. (nC)	25			
Q <sub>gs</sub> (nC)	2.0			
Q <sub>gd</sub> (nC)	2.7			
Configuration	Single			

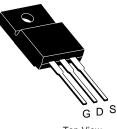
#### **FEATURES**

- Low figure-of-merit (FOM) Ron x Qa
- Low input capacitance (Ciss)
- · Reduced switching and conduction losses
- Ultra low gate charge (Q<sub>q</sub>)
- Avalanche energy rated (UIS)

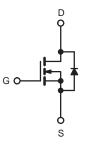
#### **APPLICATIONS**

- Server and telecom power supplies
- Switch mode power supplies (SMPS)
- Power factor correction power supplies (PFC)
- Lighting
  - High-intensity discharge (HID)
- Fluorescent ballast lighting
- Industrial

TO-220 FULLPAK



Top View



N-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS (T $_{\rm C}$ :	= 25 °C, unl	ess otherwis	se noted)			
PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			V <sub>DS</sub>	650	V	
Gate-Source Voltage			V <sub>GS</sub>	± 30	V	
Continuous Drain Current (T, = 150 °C)	V at 10 V	T <sub>C</sub> = 25 °C T <sub>C</sub> = 100 °C	1	7.0		
Continuous Drain Current $(I_J = 150^{\circ} C)$	V <sub>GS</sub> at 10 V	T <sub>C</sub> = 100 °C		5.6	A	
Pulsed Drain Current <sup>a</sup>			I <sub>DM</sub>	28	1	
Linear Derating Factor				1.67/1.5/0.3	W/°C	
Single Pulse Avalanche Energy <sup>b</sup>			E <sub>AS</sub>	86	mJ	
Maximum Power Dissipation			P <sub>D</sub>	83/83/31	W	
Operating Junction and Storage Temperature Range			T <sub>J</sub> , T <sub>stg</sub>	-55 to +150	°C	
Drain-Source Voltage Slope $T_J = 125 \text{ °C}$		al\ / / alt	50			
Reverse Diode dV/dt <sup>d</sup>			dV/dt	4.5	V/ns	
Soldering Recommendations (Peak Temperature) <sup>c</sup>	for	10 s		300	°C	

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature. b. V<sub>DD</sub> = 50 V, starting T<sub>J</sub> = 25 °C, L = 28.2 mH, R<sub>g</sub> = 25  $\Omega$ , I<sub>AS</sub> = 3.5 A.

c. 1.6 mm from case. d.  $I_{SD} \le I_D$ , dl/dt = 100 A/µs, starting  $T_J = 25$  °C.



THERMAL RESISTANCE RAT	INGS			
PARAMETER	SYMBOL	TYP.	MAX.	UNIT
Maximum Junction-to-Ambient	R <sub>thJA</sub>	-	63	°C/W
Maximum Junction-to-Case (Drain)	R <sub>thJC</sub>	-	0.6	0/10

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static		-				•	
Drain-Source Breakdown Voltage	V <sub>DS</sub>	V <sub>GS</sub> =	= 0 V, I <sub>D</sub> = 250 μA	650	-	-	V
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference	e to 25 °C, I <sub>D</sub> = 1 mA	-	0.65	-	V/°C
Gate-Source Threshold Voltage (N)	V <sub>GS(th)</sub>	V <sub>DS</sub> =	= V <sub>GS</sub> , I <sub>D</sub> = 250 μΑ	2.5	-	5	V
	_	,	V <sub>GS</sub> = ± 20 V	-	-	± 100	nA
Gate-Source Leakage	I <sub>GSS</sub>		$V_{GS} = \pm 30 \text{ V}$	-	-	± 1	μA
			= 650 V, V <sub>GS</sub> = 0 V	-	-	1	<u> </u>
Zero Gate Voltage Drain Current	I <sub>DSS</sub>		∕, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 125 °C	-	-	10	μA
Drain-Source On-State Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V		-	1.1	-	Ω
Forward Transconductance	g <sub>fs</sub>	1	= 30 V, I <sub>D</sub> = 4 A	-	16	-	S
Dynamic			_	1	1	1	<u> </u>
Input Capacitance	C <sub>iss</sub>		$V_{\rm ex} = 0.V$	-	860	-	
Output Capacitance	C <sub>oss</sub>	$V_{GS} = 0 V,$ $V_{DS} = 100 V,$ f = 1 MHz		-	120	-	-
Reverse Transfer Capacitance	C <sub>rss</sub>			-	15	-	
Effective Output Capacitance, Energy Related <sup>a</sup>	C <sub>o(er)</sub>			-	45	-	pF
Effective Output Capacitance, Time Related <sup>b</sup>	C <sub>o(tr)</sub>	- V <sub>DS</sub> = 0 V	V to 520 V, V <sub>GS</sub> = 0 V	-	62	-	
Total Gate Charge	Qg			-	25		
Gate-Source Charge	Q <sub>gs</sub>	V <sub>GS</sub> = 10 V	$I_D = 4 \text{ A}, V_{DS} = 520 \text{ V}$	-	2.0	-	nC
Gate-Drain Charge	Q <sub>gd</sub>			-	2.7	-	1
Turn-On Delay Time	t <sub>d(on)</sub>			-	25	-	
Rise Time	t <sub>r</sub>	Voo	= 520 V, I <sub>D</sub> = 4 A,	-	55	-	
Turn-Off Delay Time	t <sub>d(off)</sub>	00	$= 10 \text{ V}, \text{ R}_{\text{g}} = 9.1 \Omega$	-	70	-	ns
Fall Time	t <sub>f</sub>			-	40	-	
Gate Input Resistance	Rg	f = 1 MHz, open drain		-	3.5	-	Ω
Drain-Source Body Diode Characteristic	S	-					
Continuous Source-Drain Diode Current	I <sub>S</sub>	MOSFET syml showing the	MOSFET symbol showing the		-	7	
Pulsed Diode Forward Current	I <sub>SM</sub>	integral revers p - n junction		-	-	18	A
Diode Forward Voltage	V <sub>SD</sub>	T <sub>J</sub> = 25 °	C, I <sub>S</sub> = 4 A, V <sub>GS</sub> = 0 V	-	-	1.5	V
Reverse Recovery Time	t <sub>rr</sub>	1		-	190	-	ns
Reverse Recovery Charge	Q <sub>rr</sub>	$T_J = 2$	$5 ^{\circ}\text{C}, I_{\text{F}} = I_{\text{S}} = 4 \text{A},$	-	2.3	-	μC
Reverse Recovery Current	I <sub>RRM</sub>	dl/dt = 100 A/µs, V <sub>R</sub> = 400 V		_	10	_	A

Notes

a.  $C_{oss(er)}$  is a fixed capacitance that gives the same energy as  $C_{oss}$  while  $V_{DS}$  is rising from 0 % to 80 %  $V_{DSS}$ . b.  $C_{oss(tr)}$  is a fixed capacitance that gives the same charging time as  $C_{oss}$  while  $V_{DS}$  is rising from 0 % to 80 %  $V_{DSS}$ .



#### 50 15 V 14 V 13 V 12 V 11 V 10 V T<sub>J</sub> = 25 °C I<sub>D</sub>, Drain-to-Source Current (A) 40 9 V 8 V 7 V 30 воттом 20 10 0 0 5 10 15 20 25 30 V<sub>DS</sub>, Drain-to-Source Voltage (V) Fig. 1 - Typical Output Characteristics

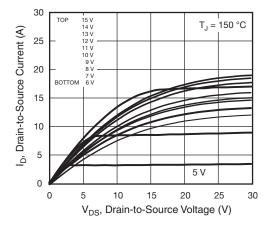


Fig. 2 - Typical Output Characteristics

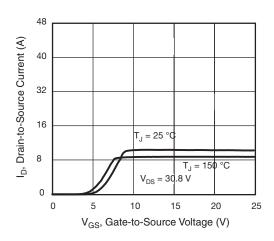


Fig. 3 - Typical Transfer Characteristics

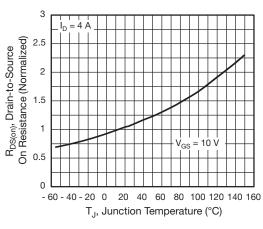


Fig. 4 - Normalized On-Resistance vs. Temperature

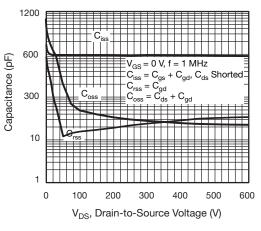


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage



Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



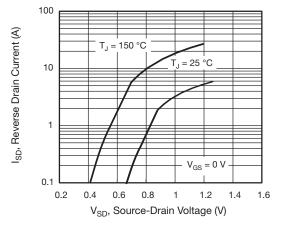


Fig. 7 - Typical Source-Drain Diode Forward Voltage

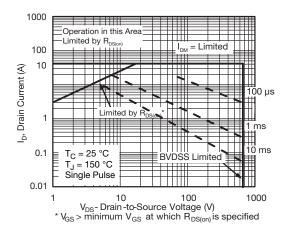


Fig. 8 - Maximum Safe Operating Area

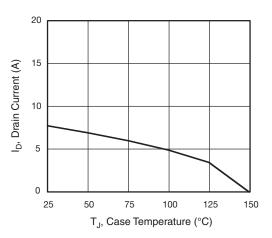


Fig. 9 - Maximum Drain Current vs. Case Temperature

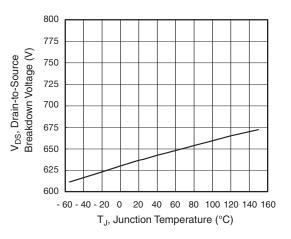


Fig. 10 - Temperature vs. Drain-to-Source Voltage

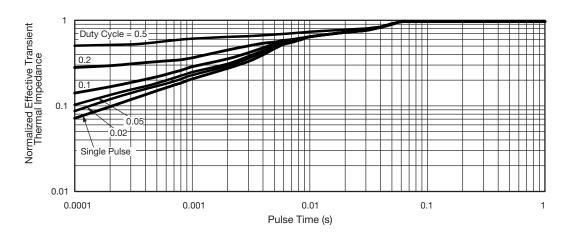


Fig. 11 - Normalized Thermal Transient Impedance, Junction-to-Case



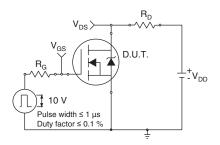


Fig. 12 - Switching Time Test Circuit

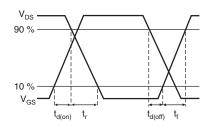


Fig. 13 - Switching Time Waveforms



Fig. 14 - Unclamped Inductive Test Circuit



Fig. 15 - Unclamped Inductive Waveforms

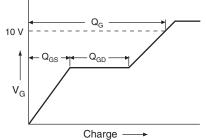


Fig. 16 - Basic Gate Charge Waveform

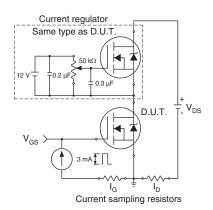
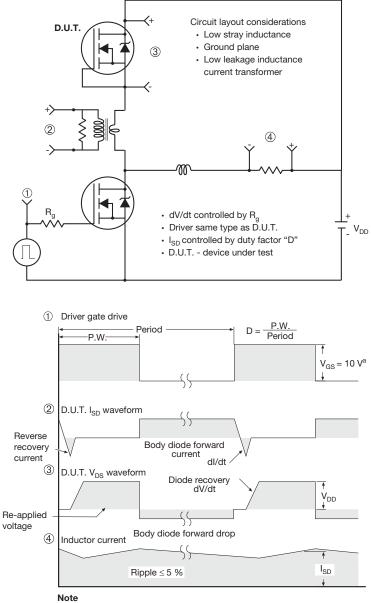


Fig. 17 - Gate Charge Test Circuit



#### Peak Diode Recovery dV/dt Test Circuit

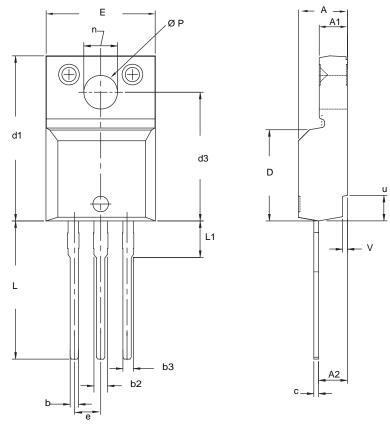


a.  $V_{GS} = 5 V$  for logic level devices

Fig. 18 - For N-Channel



### **TO-220 FULLPAK (HIGH VOLTAGE)**



	MILLI	METERS	INC	HES
DIM.	MIN.	MAX.	MIN.	MAX.
А	4.570	4.830	0.180	0.190
A1	2.570	2.830	0.101	0.111
A2	2.510	2.850	0.099	0.112
b	0.622	0.890	0.024	0.035
b2	1.229	1.400	0.048	0.055
b3	1.229	1.400	0.048	0.055
С	0.440	0.629	0.017	0.025
D	8.650	9.800	0.341	0.386
d1	15.88	16.120	0.622	0.635
d3	12.300	12.920	0.484	0.509
E	10.360	10.630	0.408	0.419
е	2.54	BSC	0.100	BSC
L	13.200	13.730	0.520	0.541
L1	3.100	3.500	0.122	0.138
n	6.050	6.150	0.238	0.242
ØP	3.050	3.450	0.120	0.136
u	2.400	2.500	0.094	0.098
V	0.400	0.500	0.016	0.020

#### Notes

1. To be used only for process drawing. 2. These dimensions apply to all TO-220, FULLPAK leadframe versions 3 leads. 3. All critical dimensions should C meet  $C_{pk} > 1.33$ . 4. All dimensions include burrs and plating thickness.

5. No chipping or package damage.



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